

# A fresh approach to surface metrology for additive manufacture

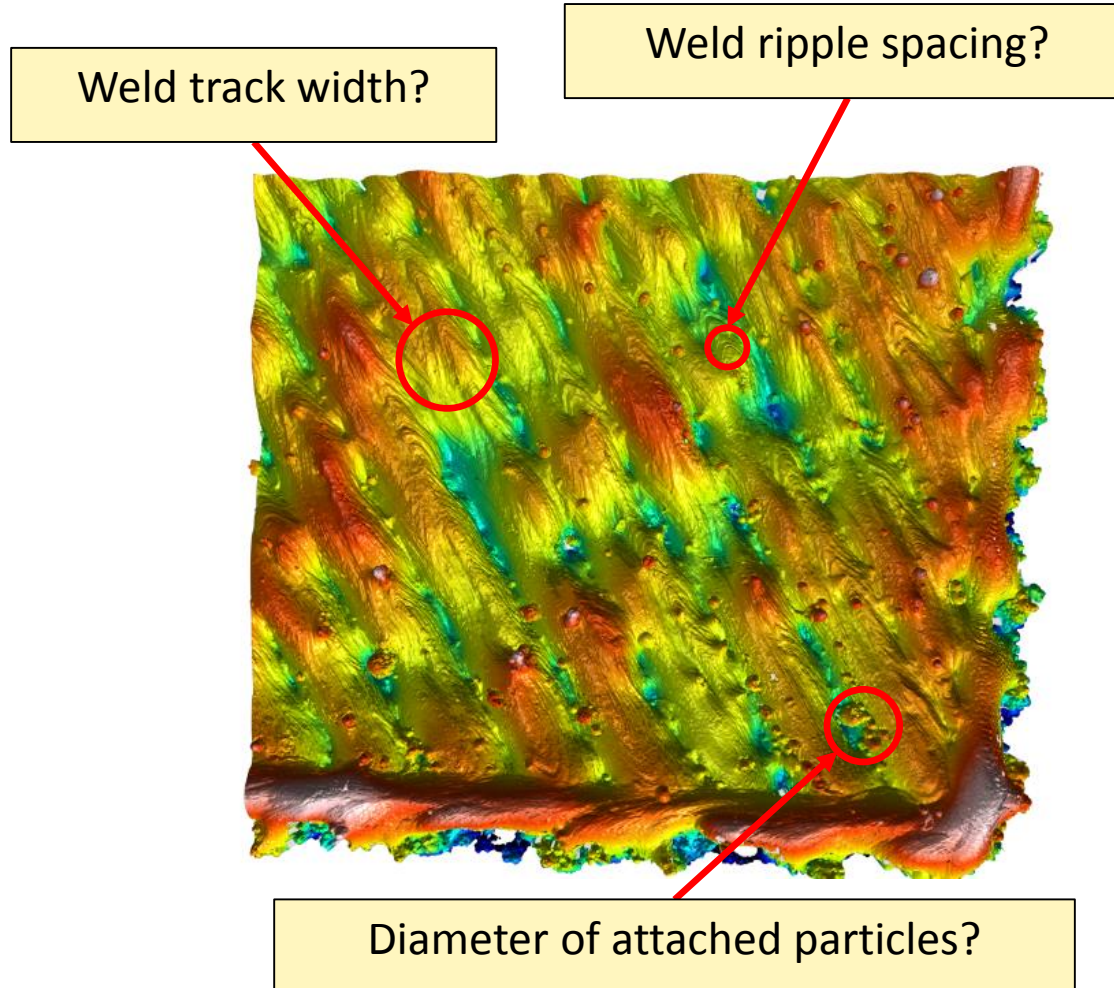
Adam Thompson, Nicola Senin, Lewis Newton, Carlos Gomez,  
Richard Leach

Manufacturing Metrology Team, Faculty of Engineering

# A paradigm shift in surface metrology

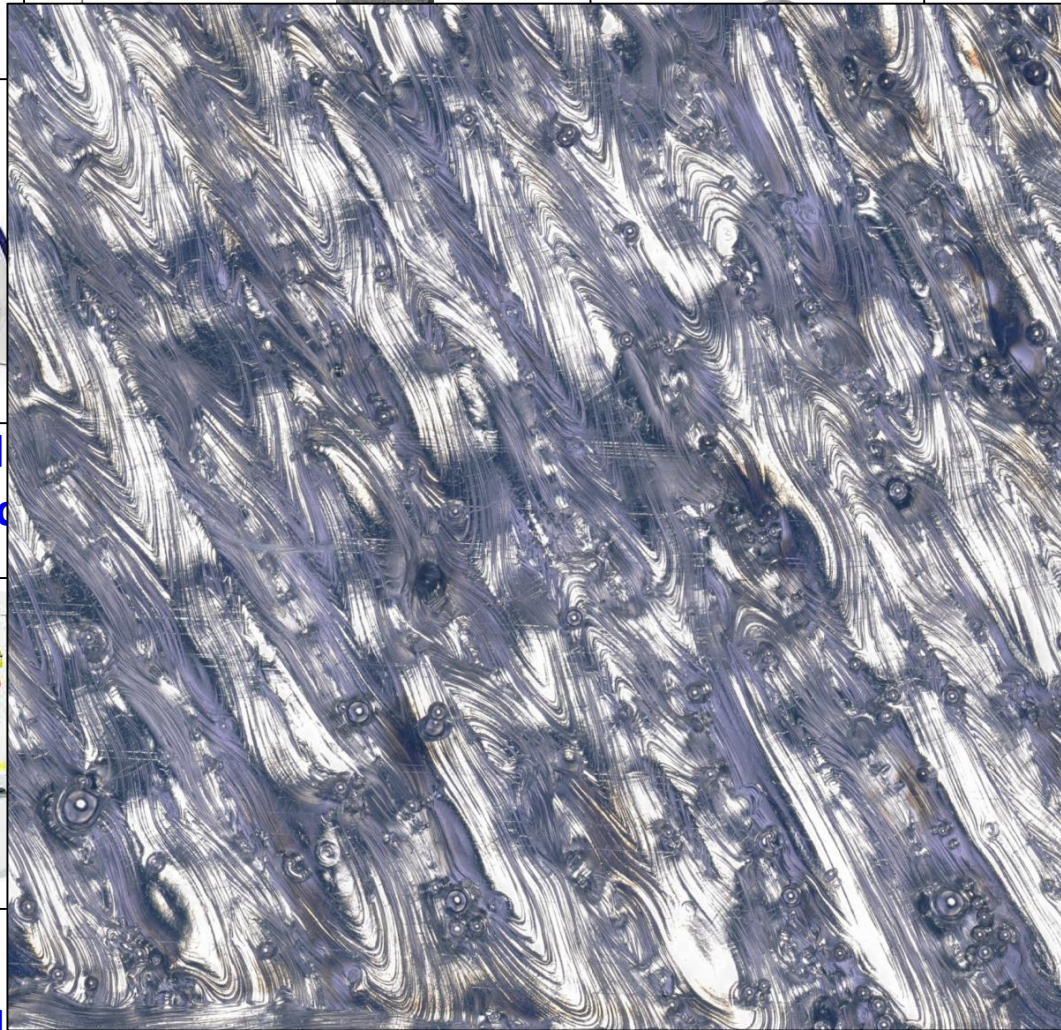


# Feature-based characterisation

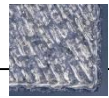




# Measurement technologies



Optical microscope



Focus stacking

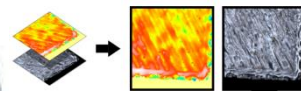


XCT

Stylus profilometer



Reference Scanning Interferometry



Focus variation



Point autofocus

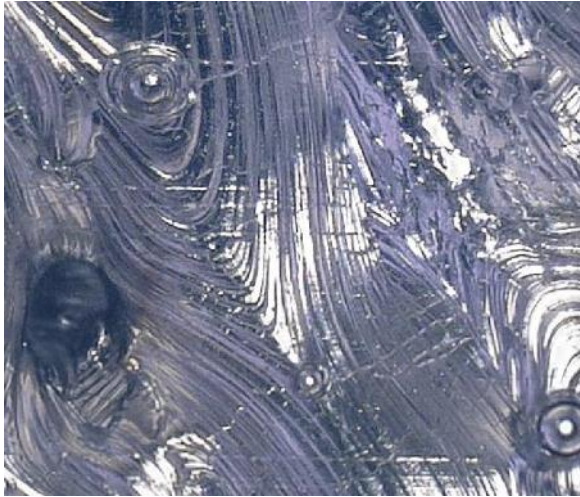
Confocal microscopy



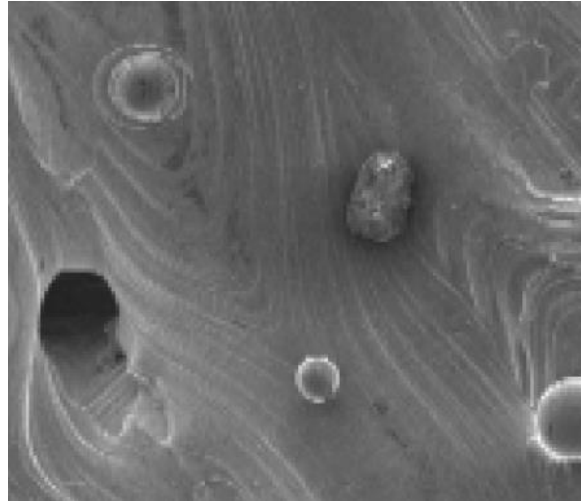


# Direct feature comparison

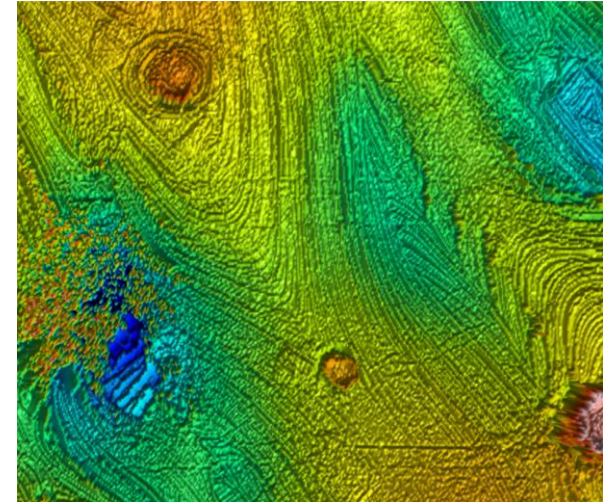
Optical microscopy



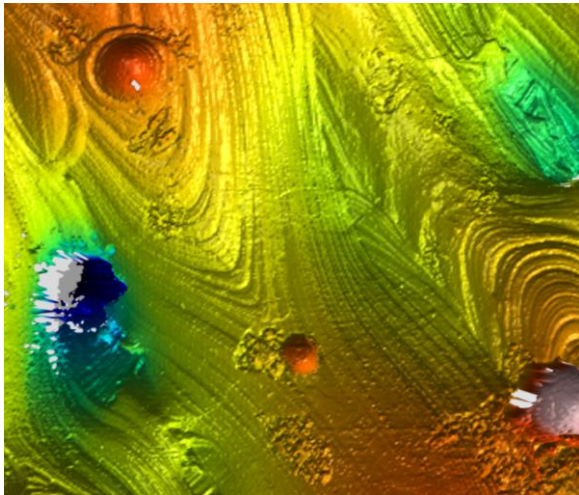
SEM



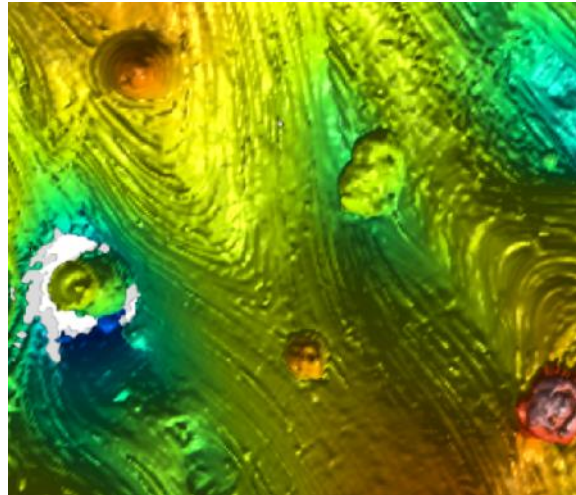
Confocal microscopy



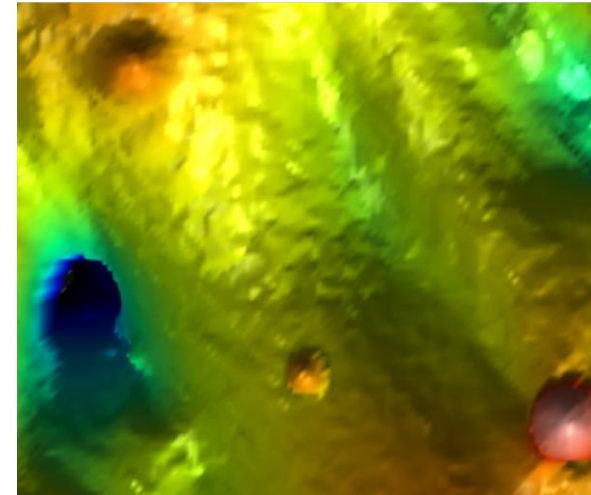
Coherence scanning interferometry



Focus variation



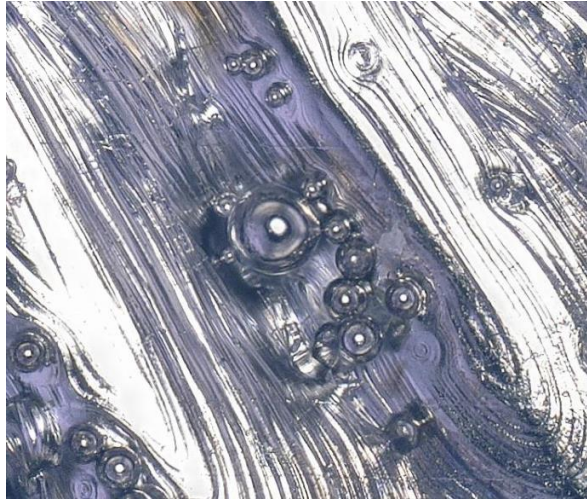
X-ray computed tomography



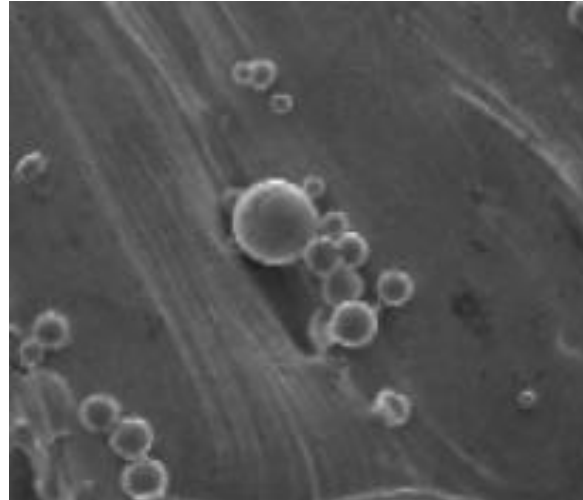


# Direct feature comparison

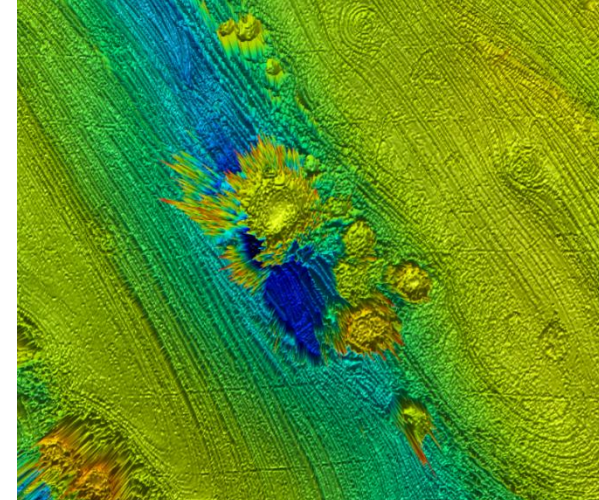
Optical microscopy



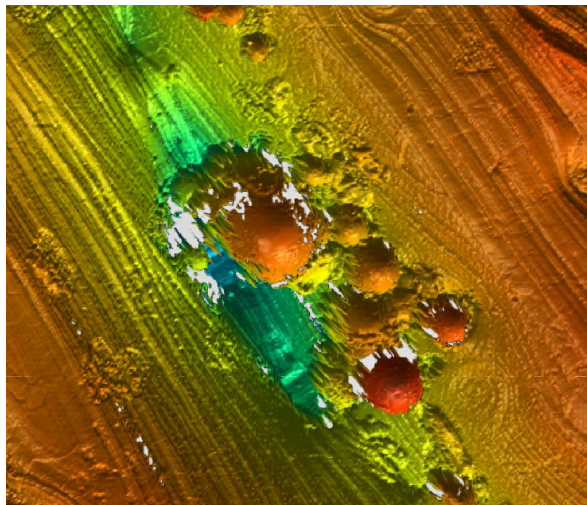
SEM



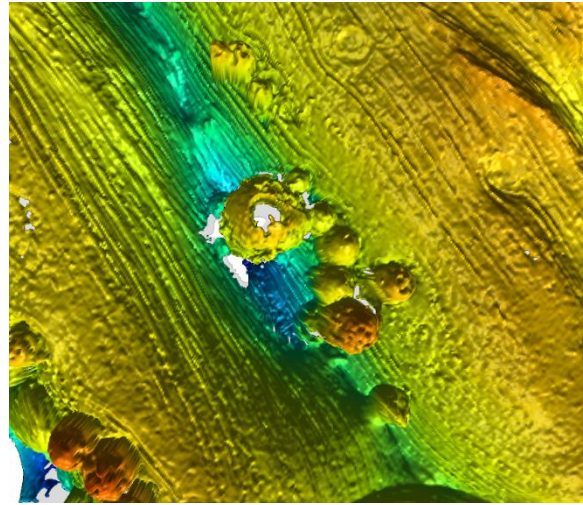
Confocal microscopy



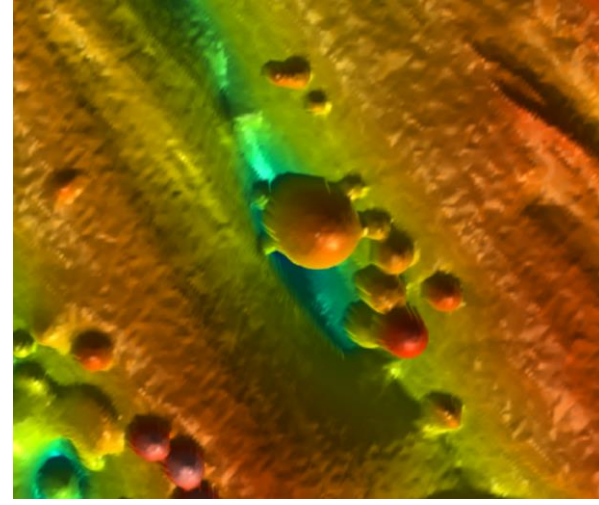
Coherence scanning interferometry



Focus variation



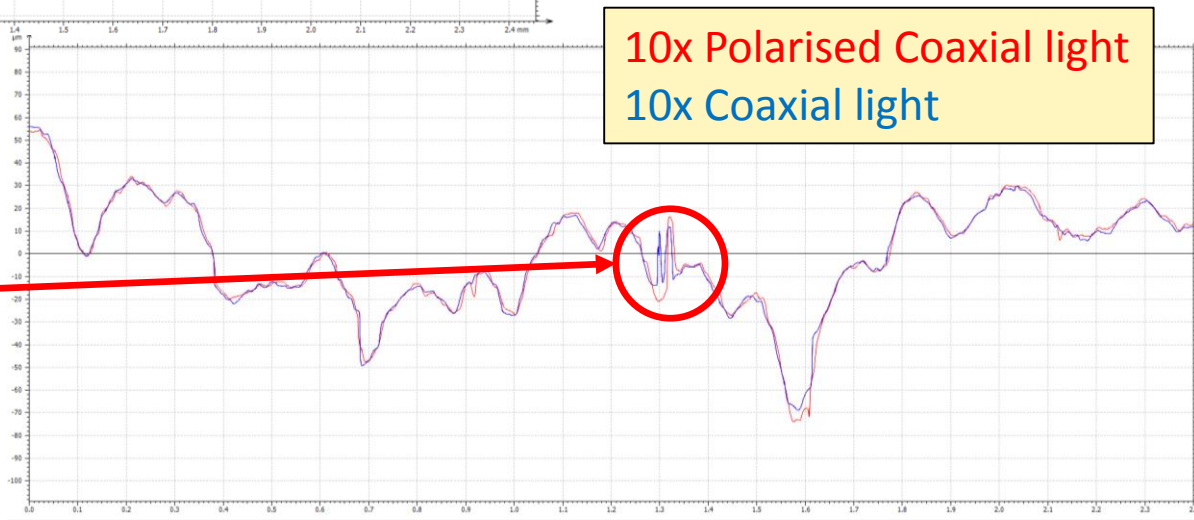
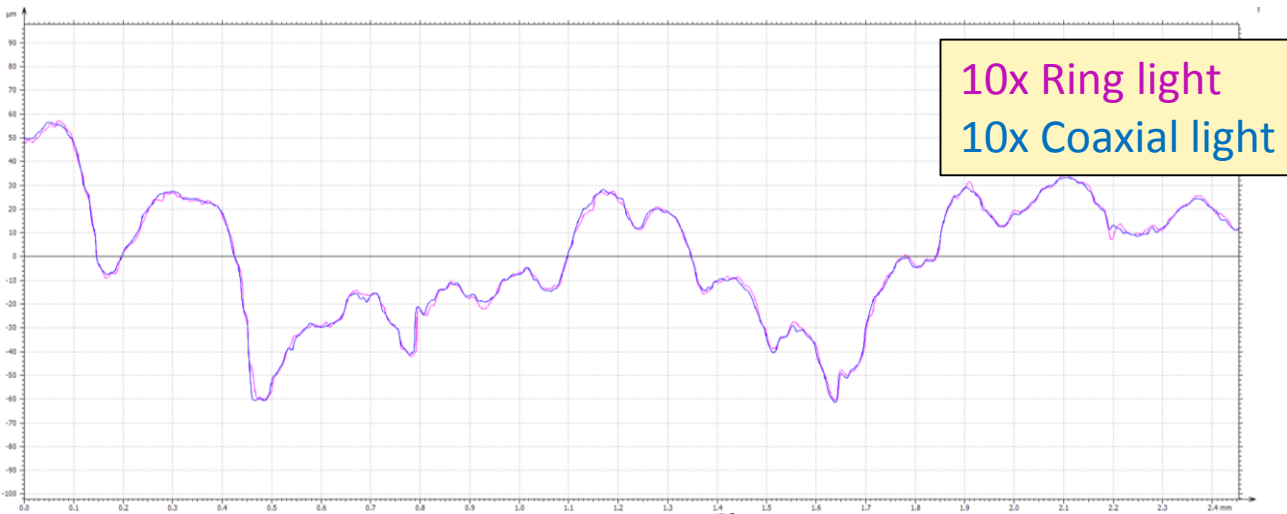
X-ray computed tomography





# Extracted profiles

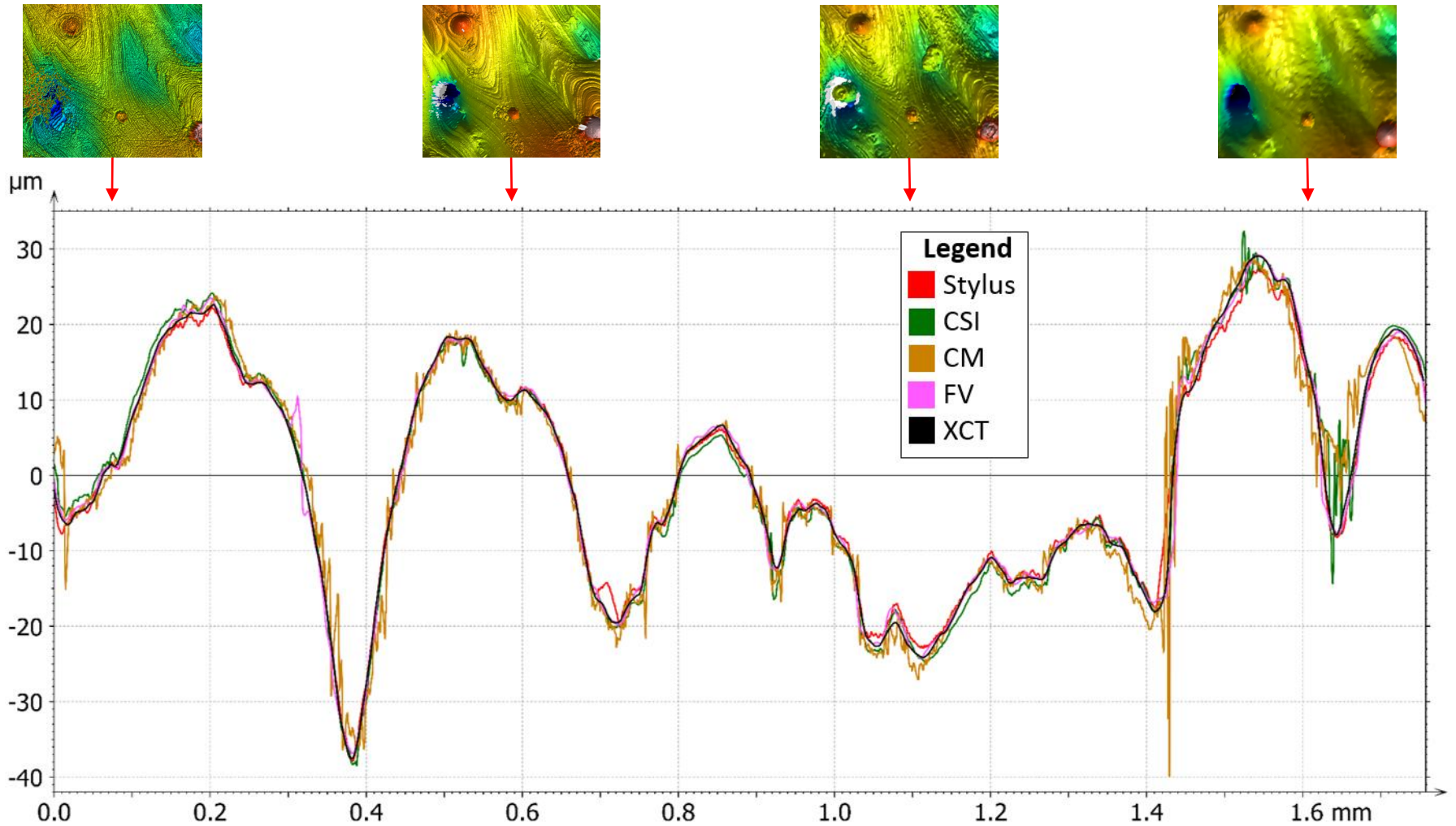
An example from focus variation (alignment by eye & software auto-registration)



Optical effect?



# Direct topographical comparison



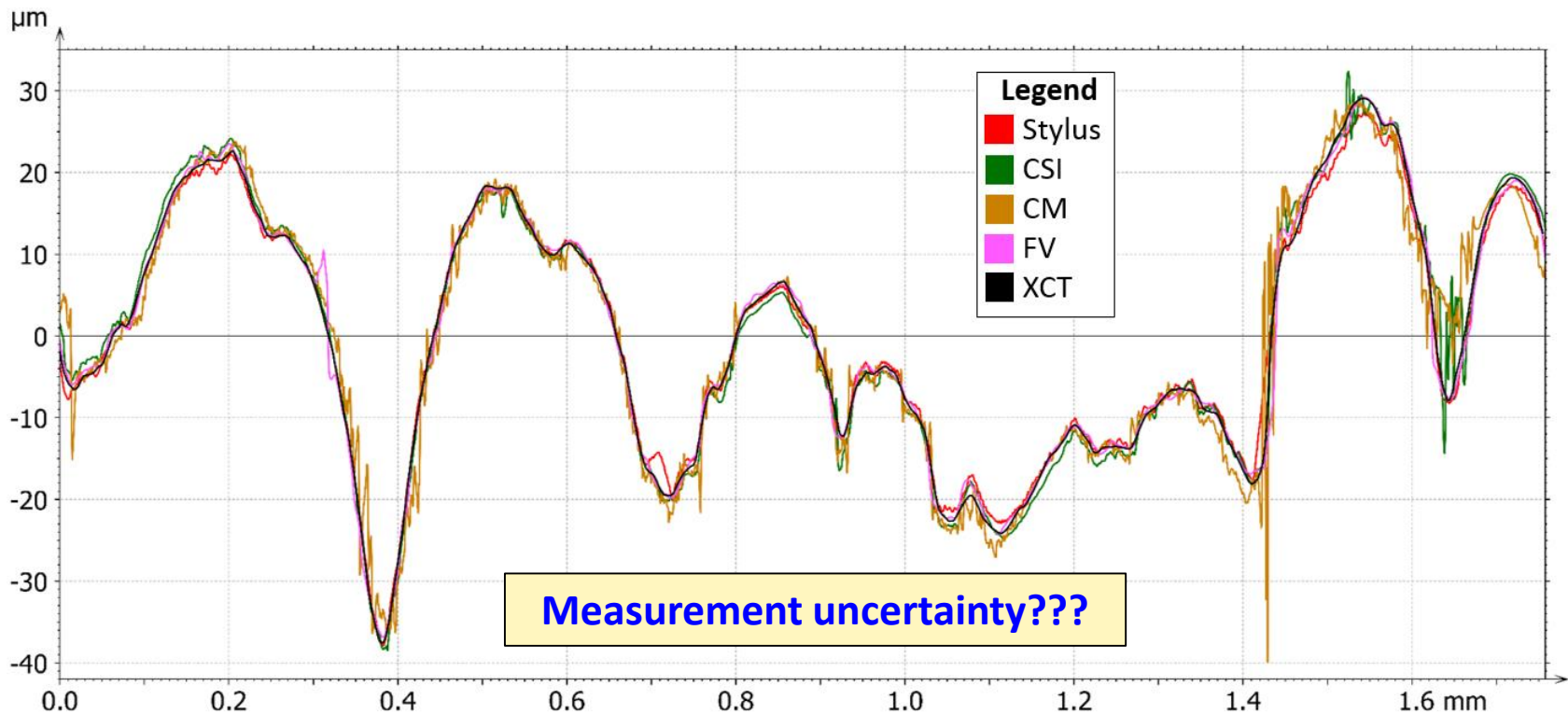




# Direct topographical comparison

## Our current work

Extending our method of surface assessment by comparison of topographies (previously **qualitative**) to a **statistically robust, quantitative** approach.



The elephant in the room:  
what about when  
we can't reach the surface?

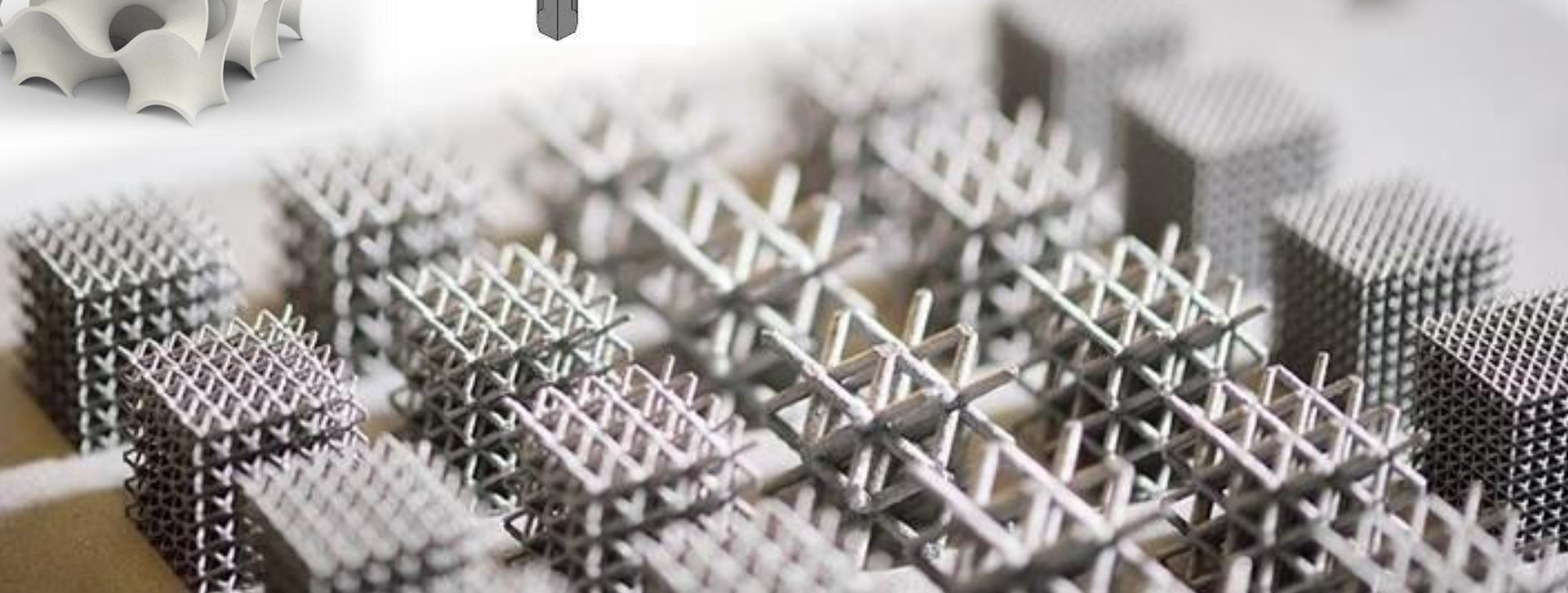
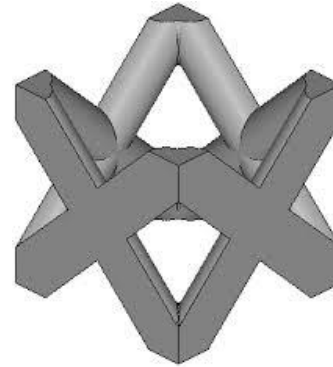
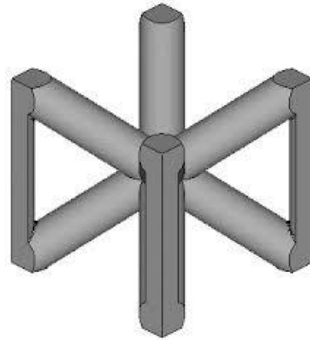
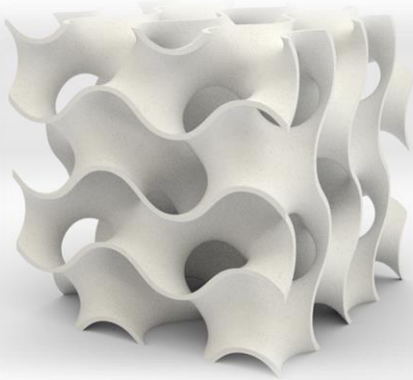
# Surfaces of objects with complex form



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**So how do we measure the surfaces of these beasts?**



# Surfaces of objects with complex form

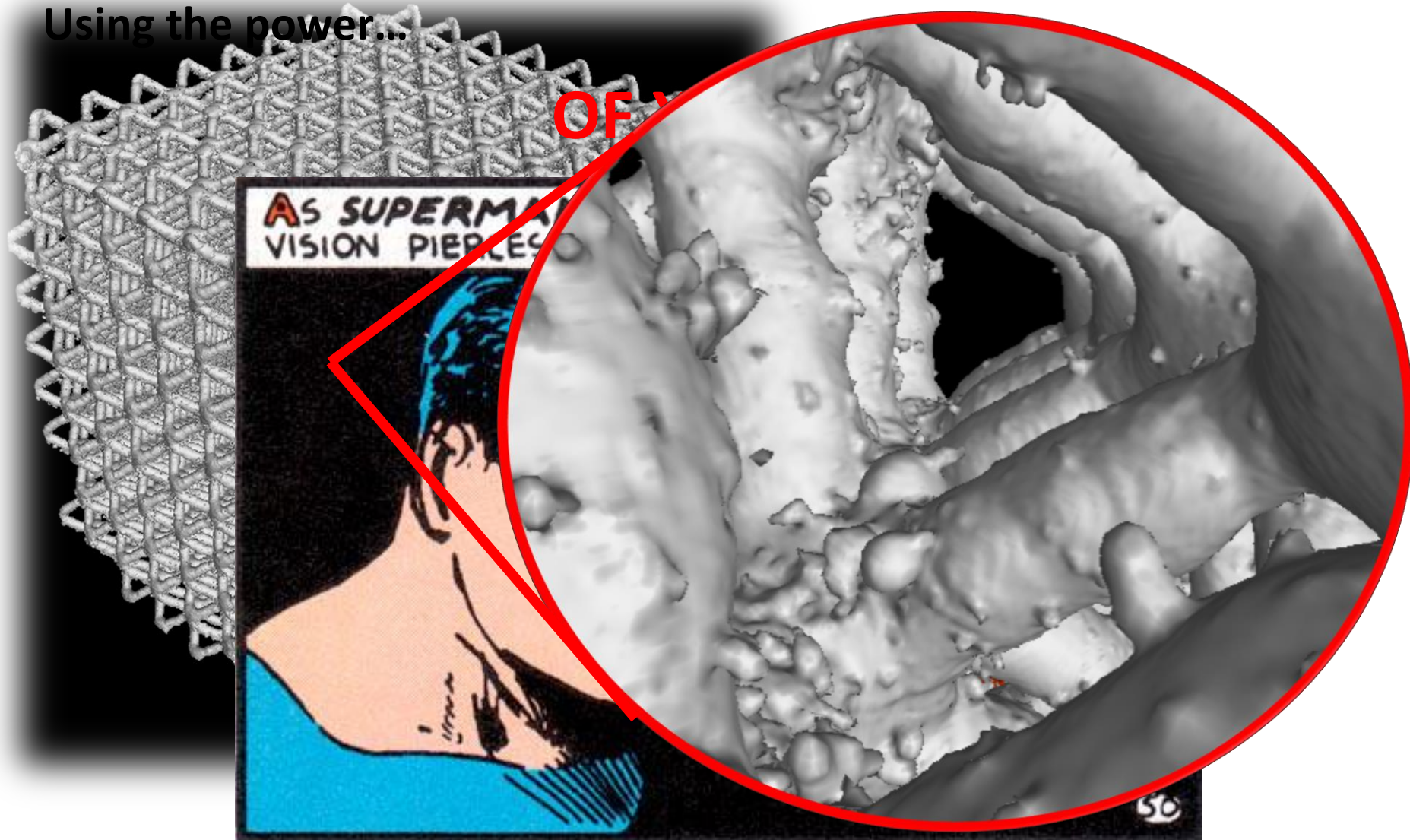


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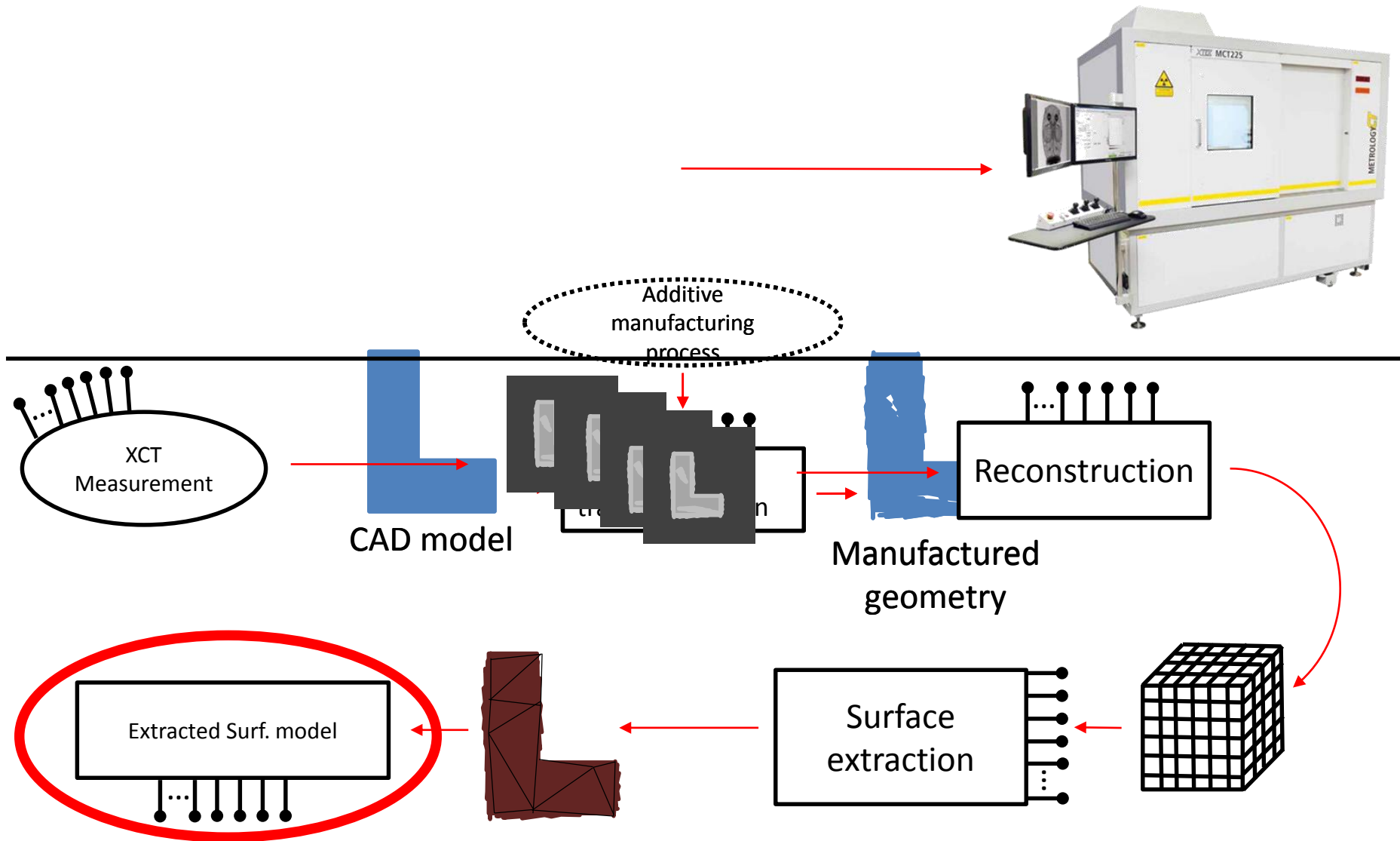
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Using the power...

OF X



# XCT Pipeline

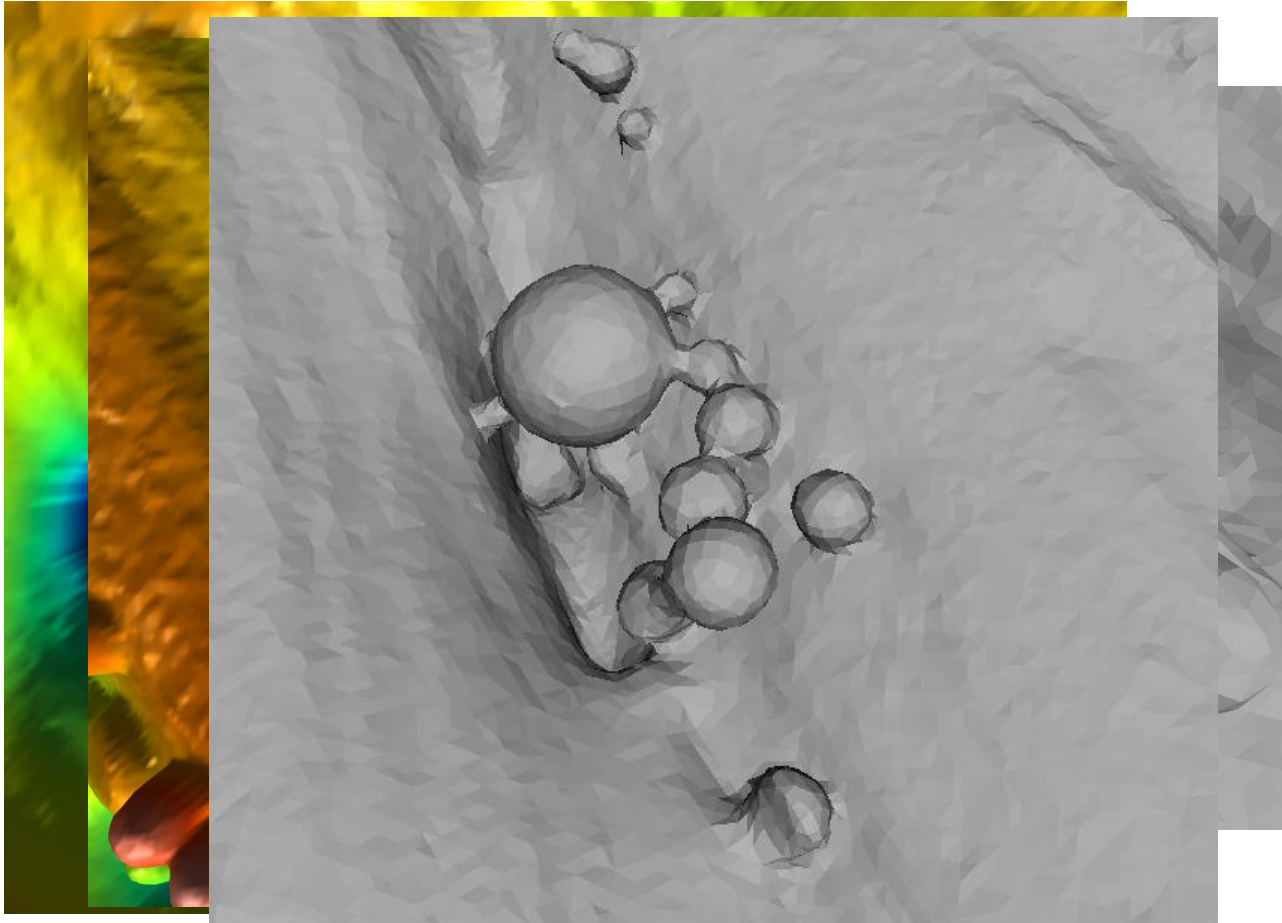


# The lost information



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# The big problem: surface determination

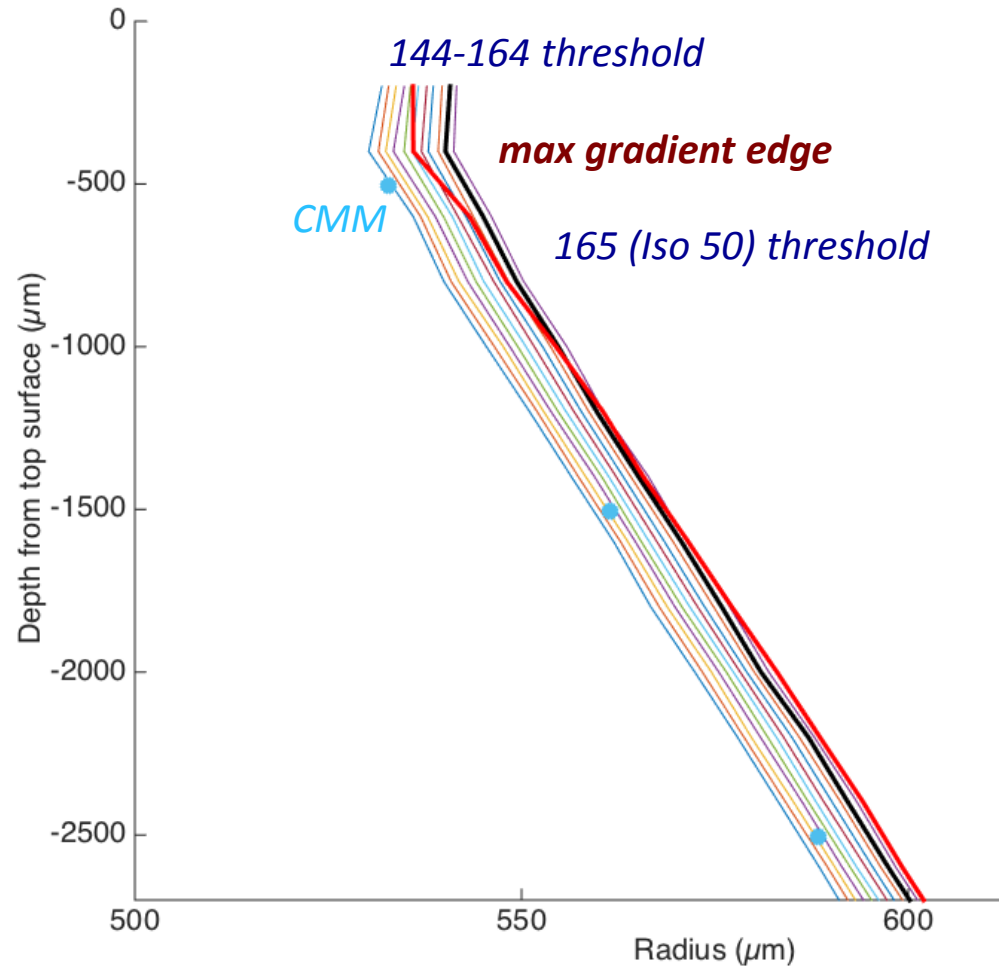
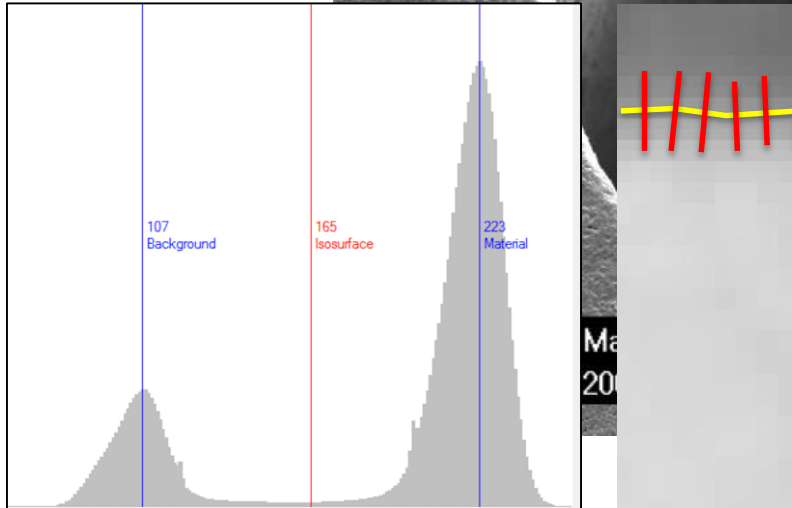
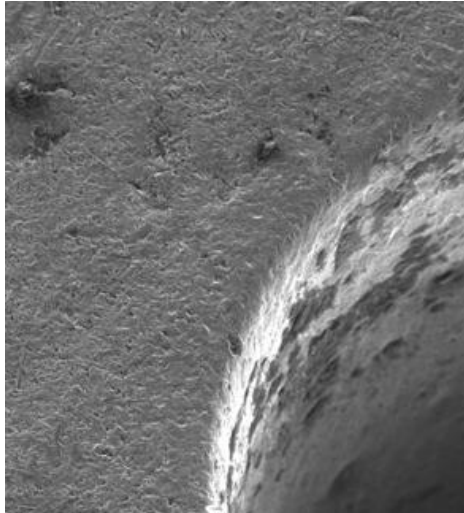


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## An example from elsewhere: microholes

*Rabani, Senin, Hemli, Butler-Smith & Leach, 2016, euspen's 16th International Conference & Exhibition, (Nottingham, UK)*

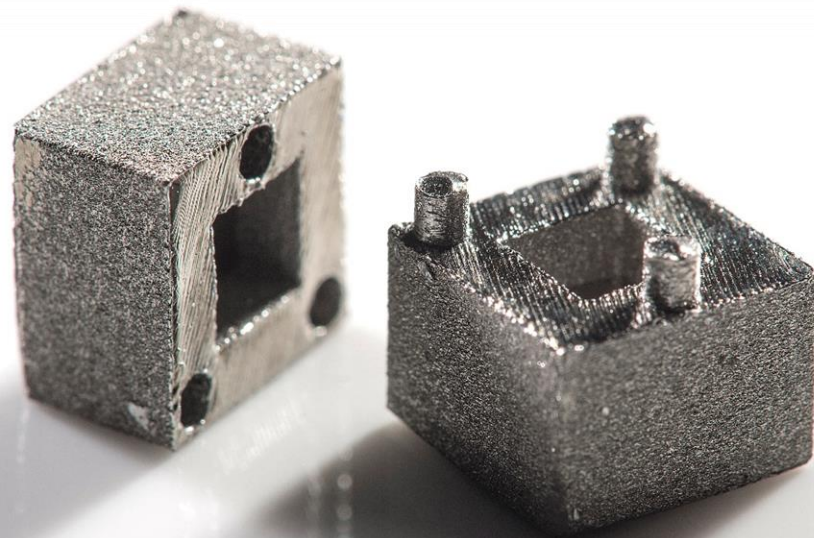


# Internal surfaces: a test case



## Selective laser melting of metals

- Hollow Ti6Al4V cube of (10 × 10 × 10) mm from an EOSINT M 280, separable to allow measurement of internal surfaces
- Top surface: comparable to previous work and representative of SLM surfaces
- Sides of recessed section used for relocation



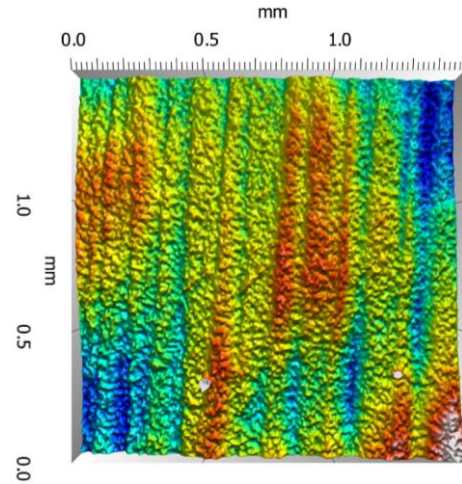
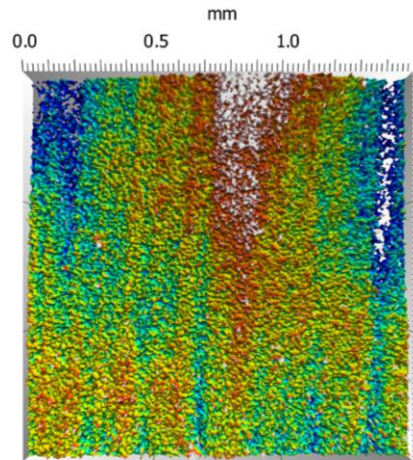


# So how does XCT compare?

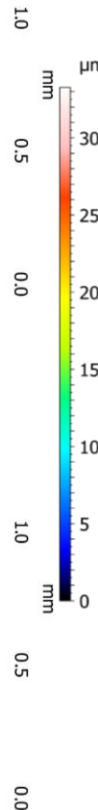


**Qualitative similarity, and many parameters in a similar ballpark...**

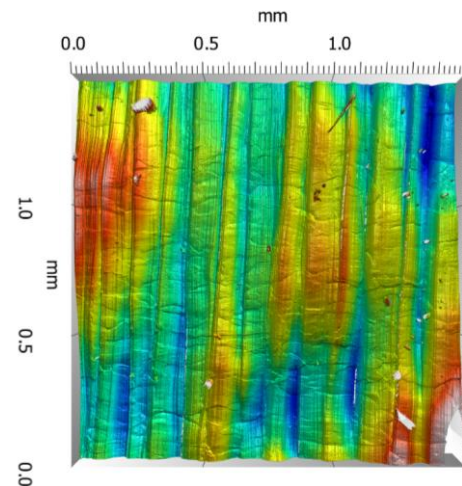
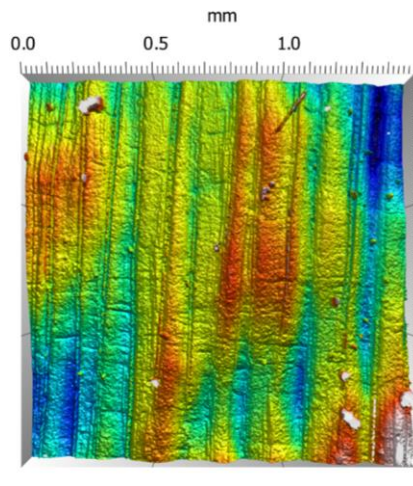
XCT 1  
**Sa = 2.63  $\mu\text{m}$**



XCT 2  
**Sa = 1.90  $\mu\text{m}$**



Focus variation  
**Sa = 1.86  $\mu\text{m}$**



Coherence scanning interferometry  
**Sa = 1.93  $\mu\text{m}$**

Shown: unfiltered raw data, while parameters were calculated for scale-limited surfaces using following cutoffs: S-filter of 11  $\mu\text{m}$  based on grid of 4 x 4 pixels in lowest resolution data, L-filter of 0.5 mm to separate roughness and waviness based on visual assessment of surfaces.

Development of a **rigorous statistical model** for direct comparison of topographies

Investigation into the specific requirements of using **XCT** for investigation of **surface texture** to develop a **good practice model**, in terms of measurement setup, reconstruction and analysis

Participation in the **CT-STARR** (CT-Surface Texture for Additive Round Robin) co-ordinated by the University of Huddersfield

Investigation into the specific requirements of using **optical instruments** for measurement of **complex AM surfaces** to develop a **good practice model** in terms of measurement setup and analysis

Development of new technology for **in-line**, layer-by-layer surface measurement

# A fresh approach to surface metrology for additive manufacture

*Thanks for your attention*

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